## University of Houston

cullen boulevard HOUSTON 4. TEXAS April 6, 1959

Dr. Joshua Lederberg Department of Genetics School of Medicine Stanford University Stanford, California

Dear Dr. Lederberg:

I have received your letter of April 2 requesting copies of my reprints. You will find the reprints of this work enclosed. I might call your attention to two papers in the March issue of Applied Microbiology (1959) that we are publishing. These deal with the interrelationship between Pseudomonads and sulfate-reducing bacteria in the deterioration of cutting fluids.

There is very little information available pertaining to the deterioration of mechanical and electronic components. In the first place this information is of military value. I sometimes hear vague comments about this type of deterioration in missiles and I suspect the best work in this field is not published. For a good background of information I suggest you obtain a copy of "Deterioration of Materials" by Greathouse and Wessel, Reinhold Publishing Corp., 430 Park Avenue, New York. This book discusses the microbial deterioration of electronic equipment and metal surfaces. If you have some particular item(s) in mind I suggest you write the Prevention of Deterioration Center, National Academy of Sciences- National Research Council, Washington, D. C. Quite often they will loan you all the information they have on a particular topic or they will give you most of the references on a deterioration topic.

There are several reports available pertaining to the deterioration of electronic equipment. These are:

Leonard, J. M., Failure of Electronic Equipment under Tropical Service Conditions, U. S. Navel Research Laboratory Report P-2475, February, 1945.

Witt, R. K., <u>Moisture and Fungus Deterioration of Electrical</u> and <u>Mechanical Properties of Plastic and Materials</u>. Paper presented at the technical program of the Electrical and Electronic Equipment Subcommittee of the U. S. Deterioration Prevention Committee, Washington, April 6, 1948.

Luce, R. H. Moisture and Fungus Deterioration of Electrical Characteristics of Hook-Up Wire - - Paper presented at the same meeting as above. I am sure Dr. Luce will be most happy to send you a copy of his paper. His address is Rennselaer Polytechnic Institute, Troy, New York.

There are quite a few papers of this type in the reference lists in Greathouse. As you can see they are reports that are not readily accessible to most investigators, however, I am sure the Deterioration Center can get you copies of the reports.

I hope this information will be of some value to you.

Kindest personal regards.

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E. O. Bennett

EOB: mbw

Encl.